

REVISIONS

LTR	DESCRIPTION	DATE (YR-MO-DA)	APPROVED
	<a href="#">查询"5962R9661401VEC"供应商</a>		

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REV STATUS OF SHEETS	REV																		
	SHEET	1	2	3	4	5	6	7	8	9	10	11	12	13					
PMIC N/A	PREPARED BY Dan Wonnell				DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444														
<b>STANDARD MICROCIRCUIT DRAWING</b>  THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS AND AGENCIES OF THE DEPARTMENT OF DEFENSE  AMSC N/A	CHECKED BY Monica Poelking				MICROCIRCUIT, DIGITAL, RADIATION HARDENED, CMOS, DUAL MONOSTABLE MULTIVIBRATOR, MONOLITHIC SILICON														
	APPROVED BY Monica Poelking																		
	DRAWING APPROVAL DATE 95-12-04				SIZE <b>A</b>	CAGE CODE <b>67268</b>	<b>5962-96614</b>												
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DISTRIBUTION STATEMENT A. Approved for public release; distribution is unlimited.

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1.3 Absolute maximum ratings. 1/ 2/ 3/

Supply voltage range ( $V_{DD}$ )	-0.5 V dc to +20 V dc
Input voltage range	-0.5 V dc to $V_{DD} + 0.5$ Vdc
DC input current, any one input	±10 mA
Device dissipation per output transistor	100 mW
Storage temperature range ( $T_{STG}$ )	-65°C to +150°C
Lead temperature (soldering, 10 seconds)	+265°C
Thermal resistance, junction-to-case ( $\theta_{JC}$ ):	
Case E	24°C/W
Case X	29°C/W
Thermal resistance, junction-to-ambient ( $\theta_{JA}$ ):	
Case E	73°C/W
Case X	114°C/W
Junction temperature ( $T_J$ )	+175°C
Maximum power dissipation at $T_A = +125^\circ\text{C}$ ( $P_D$ ): 4/	
Case E	0.68 W
Case X	0.44 W

1.4 Recommended operating conditions.

Supply voltage range ( $V_{DD}$ )	3.0 V dc to +18 V dc
Case operating temperature range ( $T_C$ )	-55°C to +125°C
Input voltage ( $V_{IN}$ )	0 V to $V_{DD}$
Output voltage ( $V_{OUT}$ )	0 V to $V_{DD}$
Radiation features:	
Total dose	1 x 10 <sup>5</sup> Rads (Si)
Single event phenomenon (SEP) effective linear energy threshold, no upsets or latchup (see 4.4.4.5)	>75 MEV/(cm <sup>2</sup> /mg) 5/
Dose rate upset (20 ns pulse)	> 5 x 10 <sup>6</sup> Rads(Si)/s 5/
Dose rate latch-up	> 2 x 10 <sup>8</sup> Rads(Si)/s 5/
Dose rate survivability	> 5 x 10 <sup>11</sup> Rads(Si)/s 5/
Neutron irradiated (device type 02)	> 1 x 10 <sup>14</sup> neutrons/cm <sup>2</sup>

2. APPLICABLE DOCUMENTS

2.1 Government specification, standards, bulletin, and handbook. Unless otherwise specified, the following specification, standards, bulletin, and handbook of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION

MILITARY

MIL-I-38535 - Integrated Circuits, Manufacturing, General Specification for.

STANDARDS

MILITARY

MIL-STD-883 - Test Methods and Procedures for Microelectronics.  
 MIL-STD-973 - Configuration Management.  
 MIL-STD-1835 - Microcircuit Case Outlines.

- 1/ Stresses above the absolute maximum rating may cause permanent damage to the device. Extended operation at the maximum levels may degrade performance and affect reliability.
- 2/ Unless otherwise specified, all voltages are referenced to  $V_{SS}$ .
- 3/ The limits for the parameters specified herein shall apply over the full specified  $V_{CC}$  range and case temperature range of -55°C to +125°C unless otherwise noted.
- 4/ If device power exceeds package dissipation capability, provide heat sinking or derate linearly (the derating is based on  $\theta_{JA}$ ) at the following rate:
 

Case E	13.7 mW/°C
Case X	8.8 mW/°C
- 5/ Guaranteed by design or process but not tested.

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BULLETIN

MILITARY  
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MIL-BUL-103 - List of Standardized Military Drawings (SMD's).

HANDBOOK

MILITARY

MIL-HDBK-780 - Standardized Military Drawings.

(Copies of the specification, standards, bulletin, and handbook required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.

3. REQUIREMENTS

3.1 Item requirements. The individual item requirements for device class M shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein. The individual item requirements for device classes Q and V shall be in accordance with MIL-I-38535 and as specified herein or as modified in the device manufacturer's Quality Management (QM) plan. The modification in the QM plan shall not affect the form, fit, or function as described herein.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-STD-883 (see 3.1 herein) for device class M and MIL-I-38535 for device classes Q and V herein.

3.2.1 Case outlines. The case outlines shall be in accordance with 1.2.4 herein.

3.2.2 Terminal connections. The terminal connections shall be as specified on figure 1.

3.2.3 Radiation test connections. The radiation test connections shall be as specified in table III herein.

3.3 Electrical performance characteristics and postirradiation parameter limits. Unless otherwise specified herein, the electrical performance characteristics and postirradiation parameter limits are as specified in table I and shall apply over the full case operating temperature range.

3.4 Electrical test requirements. The electrical test requirements shall be the subgroups specified in table IIA. The electrical tests for each subgroup are defined in table I.

3.5 Marking. The part shall be marked with the PIN listed in 1.2 herein. Marking for device class M shall be in accordance with MIL-STD-883 (see 3.1 herein). In addition, the manufacturer's PIN may also be marked as listed in MIL-BUL-103. Marking for device classes Q and V shall be in accordance with MIL-I-38535.

3.5.1 Certification/compliance mark. The compliance mark for device class M shall be a "C" as required in MIL-STD-883 (see 3.1 herein). The certification mark for device classes Q and V shall be a "QML" or "Q" as required in MIL-I-38535.

3.6 Certificate of compliance. For device class M, a certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in MIL-BUL-103 (see 6.7.2 herein). For device classes Q and V, a certificate of compliance shall be required from a QML-38535 listed manufacturer in order to supply to the requirements of this drawing (see 6.7.1 herein). The certificate of compliance submitted to DESC-EC prior to listing as an approved source of supply for this drawing shall affirm that the manufacturer's product meets, for device class M, the requirements of MIL-STD-883 (see 3.1 herein), or for device classes Q and V, the requirements of MIL-I-38535 and the requirements herein.

3.7 Certificate of conformance. A certificate of conformance as required for device class M in MIL-STD-883 (see 3.1 herein) or for device classes Q and V in MIL-I-38535 shall be provided with each lot of microcircuits delivered to this drawing.

3.8 Notification of change for device class M. For device class M, notification to DESC-EC of change of product (see 6.2 herein) involving devices acquired to this drawing is required for any change as defined in MIL-STD-973.

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3.9 Verification and review for device class M. For device class M, DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

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3.10 Microcircuit group assignment for device class M. Device class M devices covered by this drawing shall be in microcircuit group number 38 (see MIL-I-38535, appendix A).

4. QUALITY ASSURANCE PROVISIONS

4.1 Sampling and inspection. For device class M, sampling and inspection procedures shall be in accordance with MIL-STD-883 (see 3.1 herein). For device classes Q and V, sampling and inspection procedures shall be in accordance with MIL-I-38535 or as modified in the device manufacturer's quality management (QM) plan. The modification in the QM plan shall not affect form, fit, or function as described herein.

4.2 Screening. For device class M, screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. For device classes Q and V, screening shall be in accordance with MIL-I-38535, and shall be conducted on all devices prior to qualification and technology conformance inspection.

4.2.1 Additional criteria for device class M.

a. Burn-in test, method 1015 of MIL-STD-883.

(1) Test condition A, B, C, or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1015.

(2)  $T_A = +125^\circ\text{C}$ , minimum.

b. Interim and final electrical test parameters shall be as specified in table IIA herein.

4.2.2 Additional criteria for device classes Q and V.

a. The burn-in test duration, test condition and test temperature, or approved alternatives shall be as specified in the device manufacturer's QM plan in accordance with MIL-I-38535. The burn-in test circuit shall be maintained under document revision level control of the device manufacturer's Technology Review Board (TRB) in accordance with MIL-I-38535 and shall be made available to the acquiring or preparing activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1015.

b. Interim and final electrical test parameters shall be as specified in table IIA herein.

c. Additional screening for device class V beyond the requirements of device class Q shall be as specified in appendix B of MIL-I-38535 or as modified in the device manufacturer's quality management (QM) plan.

4.3 Qualification inspection for device classes Q and V. Qualification inspection for device classes Q and V shall be in accordance with MIL-I-38535. Inspections to be performed shall be those specified in MIL-I-38535 and herein for groups A, B, C, D, and E inspections (see 4.4.1 through 4.4.4).

4.3.1 Electrostatic discharge sensitivity (ESDS) qualification inspection. ESDS testing shall be performed in accordance with MIL-STD-883, method 3015. ESDS testing shall be measured only for initial qualification and after process or design changes which may affect ESDS classification.

4.4 Conformance inspection. Quality conformance inspection for device class M shall be in accordance with MIL-STD-883 (see 3.1 herein) and as specified herein. Inspections to be performed for device class M shall be those specified in method 5005 of MIL-STD-883 and herein for groups A, B, C, D, and E inspections (see 4.4.1 through 4.4.4). Technology conformance inspection for classes Q and V shall be in accordance with MIL-I-38535 or as specified in the QM plan including groups A, B, C, D, and E inspections and as specified herein except where option 2 of MIL-I-38535 permits alternate in-line control testing.

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TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions -55°C ≤ T <sub>C</sub> ≤ +125°C unless otherwise specified	Device type	Group A subgroups	Limits		Units		
					Min	Max			
Supply current	I <sub>DD</sub>	V <sub>DD</sub> = 20 V, V <sub>IN</sub> = V <sub>DD</sub> or GND  M, D, L, R 2/	All	1		2	μA		
								200	
								7.5	
				V <sub>DD</sub> = 18 V, V <sub>IN</sub> = V <sub>DD</sub> or GND	3				2
						1, 3			1
								2	30
				V <sub>DD</sub> = 5 V, V <sub>IN</sub> = V <sub>DD</sub> or GND 1/	1, 3				2
						2		60	
				V <sub>DD</sub> = 10 V, V <sub>IN</sub> = V <sub>DD</sub> or GND 1/	1, 3				2
	2	120							
Input leakage current LOW	I <sub>IL</sub>	V <sub>DD</sub> = 20 V, V <sub>IN</sub> = V <sub>DD</sub> or GND	All	1		-100	nA		
					2				-1000
						3			
Input leakage current HIGH	I <sub>IH</sub>	V <sub>DD</sub> = 20 V, V <sub>IN</sub> = V <sub>DD</sub> or GND	All	1		100	nA		
					2				1000
						3			
Output voltage, LOW	V <sub>OL</sub>	V <sub>DD</sub> = 15 V, no load V <sub>DD</sub> = 5 V, no load 1/ V <sub>DD</sub> = 10 V, no load 1/	All	1, 2, 3		50	mV		
								50	
								50	
Output voltage, HIGH	V <sub>OH</sub>	V <sub>DD</sub> = 15 V, no load 3/ V <sub>DD</sub> = 5 V, no load 1/ V <sub>DD</sub> = 10 V, no load 1/	All	1, 2, 3		14.95	V		
								4.95	
								9.95	
Low level output current (sink)	I <sub>OL</sub>	V <sub>DD</sub> = 5 V V <sub>O</sub> = 0.4 V	All	1		0.53	mA		
					2 1/			0.36	
						3 1/			0.64
		V <sub>DD</sub> = 10 V V <sub>O</sub> = 0.5 V		1				1.4	
					2 1/			0.9	
						3 1/			1.6
		V <sub>DD</sub> = 15 V V <sub>O</sub> = 1.5 V		1				3.5	
					2 1/			2.4	
						3 1/			4.2

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TABLE I. Electrical performance characteristics - Continued.

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Test	Symbol	Conditions -55°C ≤ T <sub>C</sub> ≤ +125°C unless otherwise specified	Device type	Group A subgroups	Limits		Unit
					Min	Max	
High level output current (source)	I <sub>OH</sub>	V <sub>DD</sub> = 5 V V <sub>OUT</sub> = 4.6 V	All	1		-0.53	mA
				2 1/		-0.36	
				3 1/		-0.64	
		V <sub>DD</sub> = 5 V V <sub>OUT</sub> = 2.5 V	All	1		-1.8	
				2 1/		-1.15	
				3 1/		-2.0	
	V <sub>DD</sub> = 10 V V <sub>OUT</sub> = 9.5 V	All	1		-1.4		
			2 1/		-0.9		
			3 1/		-1.6		
	V <sub>DD</sub> = 15 V V <sub>OUT</sub> = 13.5 V	All	1		-3.5		
			2 1/		-2.4		
			3 1/		-4.2		
Input voltage	V <sub>IL</sub>	V <sub>DD</sub> = 5 V V <sub>OH</sub> > 4.5 V, V <sub>OL</sub> < 0.5 V	All	1, 2, 3		1.5	V
		V <sub>DD</sub> = 10 V V <sub>OH</sub> > 9.0 V, V <sub>OL</sub> < 1.0 V 1/		1, 2, 3		3	
		V <sub>DD</sub> = 15 V V <sub>OH</sub> > 13.5 V, V <sub>OL</sub> < 1.5 V		1, 2, 3		4	
	V <sub>IH</sub>	V <sub>DD</sub> = 5 V V <sub>OH</sub> > 4.5 V, V <sub>OL</sub> < 0.5 V	All	1, 2, 3	3.5		
		V <sub>DD</sub> = 10 V V <sub>OH</sub> > 9.0 V, V <sub>OL</sub> < 1.0 V 1/		1, 2, 3	7		
		V <sub>DD</sub> = 15 V V <sub>OH</sub> > 13.5 V, V <sub>OL</sub> < 1.5 V		1, 2, 3	11		
N threshold voltage	V <sub>NTH</sub>	V <sub>DD</sub> = 10 V, I <sub>SS</sub> = -10 μA M, D, L, R 2/	All	1	-0.7	-2.8	V
					-0.2	-2.8	
N threshold voltage, delta	ΔV <sub>NTH</sub>	V <sub>DD</sub> = 10 V, I <sub>SS</sub> = -10 μA, M, D, L, R 2/	All	1		±1.0	
P threshold voltage	V <sub>PTH</sub>	V <sub>SS</sub> = 0.0 V, I <sub>DD</sub> = 10 μA M, D, L, R 2/	All	1	0.7	2.8	
				1	0.2	2.8	
P threshold voltage, delta	ΔV <sub>PTH</sub>	V <sub>SS</sub> = 0.0 V, I <sub>DD</sub> = 10 μA M, D, L, R 2/	All	1		±1.0	

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TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions -55°C ≤ T <sub>C</sub> ≤ +125°C unless otherwise specified	Device type	Group A subgroups	Limits		Unit
					Min	Max	
Functional tests		V <sub>DD</sub> = 2.8 V, V <sub>IN</sub> = V <sub>DD</sub> or GND	All	7	V <sub>OH</sub> > V <sub>DD</sub> /2	V <sub>OL</sub> < V <sub>DD</sub> /2	V
		V <sub>DD</sub> = 20 V, V <sub>IN</sub> = V <sub>DD</sub> or GND		7			
		V <sub>DD</sub> = 18 V, V <sub>IN</sub> = V <sub>DD</sub> or GND	All	8A			
		M, D, L, R 2/	All	7			
		V <sub>DD</sub> = 3.0 V, V <sub>IN</sub> = V <sub>DD</sub> or GND	All	8B			
		M, D, L, R 2/	All	7			
Input capacitance	C <sub>IN</sub>	Any input, See 4.4.1c 1/	All	4		7.5	pF
Propagation delay time, +TR, -TR to Q, Q̄	t <sub>PHL1</sub> , t <sub>PLH1</sub>	V <sub>DD</sub> = 5 V, V <sub>IN</sub> = V <sub>DD</sub> or GND R <sub>X</sub> = 5 K to 10 KΩ, C <sub>X</sub> ≥ 15 pF 4/	All	9		500	ns
				10, 11		675	
		M, D, L, R 2/		9		675	
		V <sub>DD</sub> = 10 V 1/, 4/, 5/		9		250	
		V <sub>DD</sub> = 15 V 1/, 4/, 5/		9		200	
Propagation delay time, reset C <sub>X</sub> ≥ 15 pF	t <sub>PHL2</sub> , t <sub>PLH2</sub>	V <sub>DD</sub> = 5 V 1/, 4/	All	9		450	ns
		V <sub>DD</sub> = 10 V 1/, 4/, 5/		9		250	
		V <sub>DD</sub> = 15 V 1/, 4/, 5/		9		150	
Transition time	t <sub>TLH1</sub>	V <sub>DD</sub> = 5 V, V <sub>IN</sub> = V <sub>DD</sub> or GND, R <sub>X</sub> = 5 K to 10 KΩ, C <sub>X</sub> ≥ 15 pF 4/	All	9		200	ns
				10, 11		270	
		V <sub>DD</sub> = 10 V 1/, 4/, 5/		9		100	
		V <sub>DD</sub> = 15 V 1/, 4/, 5/		9		80	
Transition time	t <sub>THL1</sub>	V <sub>DD</sub> = 5 V, V <sub>IN</sub> = V <sub>DD</sub> or GND, R <sub>X</sub> = 5 K to 10 KΩ, C <sub>X</sub> ≥ 15 pF to 10,000 pF 4/	All	9		200	ns
				10, 11		270	
		V <sub>DD</sub> = 10 V 1/, 4/		9		100	
		V <sub>DD</sub> = 15 V 1/, 4/		9		80	
Transition time C <sub>X</sub> = 0.01 μF to 0.1 μF	t <sub>TLH2</sub> , t <sub>THL2</sub>	V <sub>DD</sub> = 5 V 1/, 4/	All	9		300	ns
		V <sub>DD</sub> = 10 V 1/, 4/, 6/		9		150	
		V <sub>DD</sub> = 15 V 1/, 4/, 6/		9		130	
Transition time C <sub>X</sub> = 0.1 μF to 1 μF	t <sub>THL3</sub>	V <sub>DD</sub> = 5 V 1/, 4/	All	9		500	ns
		V <sub>DD</sub> = 10 V 1/, 4/, 5/		9		300	
		V <sub>DD</sub> = 15 V 1/, 4/, 5/		9		100	
Pulse width match between circuits in same package	t <sub>WM</sub>	V <sub>DD</sub> = 5 V 1/, 4/, 7/	All	9		10	%
		V <sub>DD</sub> = 10 V 1/, 4/, 7/		9		15	
		V <sub>DD</sub> = 15 V 1/, 4/, 7/		9		15	

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TABLE 1. Electrical performance characteristics - Continued.

Test	Symbol	Conditions -55°C ≤ T <sub>C</sub> ≤ +125°C unless otherwise specified		Device type	Group A subgroups	Limits		Unit
						Min	Max	
Minimum reset pulse width	t <sub>W</sub>	CX = 15 pF 4/, 6/	V <sub>DD</sub> = 5 V 1/	All	9		200	ns
			V <sub>DD</sub> = 10 V 1/				80	
			V <sub>DD</sub> = 15 V 1/				60	
		CX = 1000 pF 4/, 6/	V <sub>DD</sub> = 5 V 1/	All	9		1200	ns
			V <sub>DD</sub> = 10 V 1/				600	
			V <sub>DD</sub> = 15 V 1/				500	
Minimum reset pulse width	t <sub>W</sub>	CX = 0.1 μF 4/, 6/	V <sub>DD</sub> = 5 V 1/	All	9		50	ns
			V <sub>DD</sub> = 10 V 1/				30	
			V <sub>DD</sub> = 15 V 1/				20	
Trigger rise or fall time	t <sub>RTR</sub> , t <sub>FTR</sub>	V <sub>DD</sub> = 5 V to 15 V 1/		All	9		100	μs

- 1/ These tests are controlled via design or process and are not directly tested. These parameters are characterized on initial design release and upon design changes which affect these characteristics.
- 2/ Devices supplied to this drawing will meet all levels M, D, L, R of irradiation. However, this device is only tested at the 'R' level. When performing post irradiation electrical measurements for any RHA level, T<sub>A</sub> = +25°C.
- 3/ For accuracy, voltage is measured differentially to V<sub>DD</sub>. Limit is 0.050 V Max.
- 4/ C<sub>L</sub> = 50 pF, R<sub>i</sub> = 200 kΩ, Input t<sub>R</sub>, t<sub>F</sub> < 20 ns.
- 5/ R<sub>X</sub> = 5 kΩ to 10 MΩ.
- 6/ R<sub>X</sub> = 100 kΩ.
- 7/ R<sub>X</sub> = 10 kΩ.

Device type	01 and 02
Case outlines	E and X
Terminal number	Terminal symbol
1	CX1
2	RXCX(1)
3	RESET(1)
4	+TR(1)
5	-TR(1)
6	Q1
7	Q1
8	V <sub>SS</sub>
9	Q2
10	Q2
11	-TR(2)
12	+TR(2)
13	RESET(2)
14	RXCX(2)
15	CX2
16	V <sub>DD</sub>

Note: Terminals 1, 8, 15 are electrically connected internally.

FIGURE 1. Terminal connections.

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4.4.1 Group A inspection.

a. Tests shall be as specified in table IIA herein.

b. For device class M, subgroups 7 and 8 tests shall be sufficient to verify the truth table. For device classes Q and V, subgroups 7 and 8 shall include verifying the functionality of the device.

c. Subgroup 4 ( $C_{IN}$  measurement) shall be measured only for the initial qualification and after process or design changes which may affect capacitance.  $C_{IN}$  shall be measured between the designated terminal and GND at a frequency of 1 MHz. Tests shall be sufficient to validate the limits defined in table I herein.

4.4.2 Group C inspection. The group C inspection end-point electrical parameters shall be as specified in table IIA herein.

4.4.2.1 Additional criteria for device class M. Steady-state life test conditions, method 1005 of MIL-STD-883:

a. Test condition A, B, C or D. The test circuit shall be maintained by the manufacturer under document revision level control and shall be made available to the preparing or acquiring activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1005.

b.  $T_A = +125^\circ\text{C}$ , minimum.

c. Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

4.4.2.2 Additional criteria for device classes Q and V. The steady-state life test duration, test condition and test temperature, or approved alternatives shall be as specified in the device manufacturer's QM plan in accordance with MIL-I-38535. The test circuit shall be maintained under document revision level control by the device manufacturer's TRB, in accordance with MIL-I-38535, and shall be made available to the acquiring or preparing activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in test method 1005.

4.4.3 Group D inspection. The group D inspection end-point electrical parameters shall be as specified in table IIA herein.

4.4.4 Group E inspection. Group E inspection is required only for parts intended to be marked as radiation hardness assured (see 3.5 herein). RHA levels for device classes M, Q and V shall be as specified in MIL-I-38535. End-point electrical parameters shall be as specified in table IIA herein.

4.4.4.1 Total dose irradiation testing. Total dose irradiation testing shall be performed in accordance with MIL-STD-883 method 1019 and as specified herein.

4.4.4.1.1 Accelerated aging test. Accelerated aging tests shall be performed on all devices requiring a RHA level greater than 5k rads(Si). The post-anneal end-point electrical parameter limits shall be as specified in table I herein and shall be the pre-irradiation end-point electrical parameter limit at  $+25^\circ\text{C} \pm 5^\circ\text{C}$ . Testing shall be performed at initial qualification and after any design or process changes which may affect the RHA response of the device.

4.4.4.2 Neutron irradiation. Neutron irradiation for device type 02, shall be conducted in wafer form using a neutron fluence of approximately  $1 \times 10^{14}$  neutrons/cm<sup>2</sup>.

4.4.4.3 Dose rate induced latchup testing. Dose rate induced latchup testing shall be performed in accordance with test method 1020 of MIL-STD-883 and as specified herein (see 1.4 herein). Tests shall be performed on devices, SEC, or approved test structures at technology qualification and after any design or process changes which may effect the RHA capability of the process.

4.4.4.4 Dose rate upset testing. Dose rate upset testing shall be performed in accordance with test method 1021 of MIL-STD-883 and herein (see 1.4 herein).

a. Transient dose rate upset testing shall be performed at initial qualification and after any design or process changes which may effect the RHA performance of the devices. Test 10 devices with 0 defects unless otherwise specified.

b. Transient dose rate upset testing for class Q and V devices shall be performed as specified by a TRB approved radiation hardness assurance plan and MIL-I-38535.

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TABLE IIA. Electrical test requirements.

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	Subgroups (in accordance with MIL-STD-883, TM 5005, table I)	Subgroups (in accordance with MIL-I-38535, table III)	
	Device class M	Device class Q	Device class V
Interim electrical parameters (see 4.2)	1,7,9	1,7,9	1,7,9
Final electrical parameters (see 4.2)	1,2,3,7,8,9,10,11 1/	1,2,3,7,8,9,10,11 1/	1,2,3,7,8,9,10,11 2/ 3/
Group A test requirements (see 4.4)	1,2,3,4,7,8,9,10,11	1,2,3,4,7,8,9,10,11	1,2,3,4,7,8,9,10,11
Group C end-point electrical parameters (see 4.4)	1,2,3,7,8,9,10,11	1,2,3,7,8,9,10,11	1,2,3,7,8,9,10,11 3/
Group D end-point electrical parameters (see 4.4)	1,7,9	1,7,9	1,7,9
Group E end-point electrical parameters (see 4.4)	1,7,9	1,7,9	1,7,9

- 1/ PDA applies to subgroup 1 and 7.
- 2/ PDA applies to subgroups 1, 7 and 9 and deltas.
- 3/ Delta limits as specified in table IIB shall be required where specified, and the delta limits shall be completed with reference to the zero hour electrical parameters (see Table I)

Table IIB. Burn-in and operating life test Delta parameters (+25°C)

Parameter	Symbol	Delta Limits
Supply current	$I_{DD}$	$\pm 0.2 \mu A$
Output current (sink) $V_{DD} = 5.0 V$	$I_{OL}$	$\pm 20\%$
Output current (source) $V_{DD} = 5.0 V, V_{OUT} = 4.6 V$	$I_{OH}$	$\pm 20\%$

4.4.4.5 Single event phenomena (SEP). SEP testing shall be required on class V devices (see 1.4 herein). SEP testing shall be performed on a technology process on the Standard Evaluation Circuit (SEC) or alternate SEP test vehicle as approved by the qualifying activity at initial qualification and after any design or process changes which may affect the upset or latchup characteristics. The recommended test conditions for SEP are as follows:

- a. The ion beam angle of incidence shall be between normal to the die surface and 60° to the normal, inclusive (i.e.  $0^\circ \leq \text{angle} \leq 60^\circ$ ). No shadowing of the ion beam due to fixturing or package related effects is allowed.
- b. The fluence shall be  $\geq 100$  errors or  $\geq 10^6$  ions/cm<sup>2</sup>.
- c. The flux shall be between  $10^2$  and  $10^5$  ions/cm<sup>2</sup>/s. The cross-section shall be verified to be flux independent by measuring the cross-section at two flux rates which differ by at least an order of magnitude.
- d. The particle range shall be  $\geq 20$  microns in silicon.
- e. The test temperature shall be +25°C and the maximum rated operating temperature  $\pm 10^\circ C$ .
- f. Bias conditions shall be defined by the manufacturer for latchup measurements.
- g. Test four devices with zero failures.

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Table III. Irradiation test connections. 1/

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Open	Ground	$V_{DD} = 10\text{ V} \pm 0.5\text{ V}$
2,6,7,9,10,14	1,8,15	3,4,5,11,12,13,16

1/ Each pin except  $V_{DD}$  and GND will have a series resistor of  $47\text{K}\Omega \pm 5\%$ , for irradiation testing.

4.5 Methods of inspection. Methods of inspection shall be as specified as follows:

4.5.1 Voltage and current. Unless otherwise specified, all voltages given are referenced to the microcircuit GND terminal. Currents given are conventional current and positive when flowing into the referenced terminal.

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-STD-883 (see 3.1 herein) for device class M and MIL-I-38535 for device classes Q and V.

6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use for Government microcircuit applications (original equipment), design applications, and logistics purposes.

6.1.1 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.

6.1.2 Substitutability. Device class Q devices will replace device class M devices.

6.2 Configuration control of SMD's. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished in accordance with MIL-STD-973 using DD Form 1692, Engineering Change Proposal.

6.3 Record of users. Military and industrial users shall inform Defense Electronics Supply Center when a system application requires configuration control and which SMD's are applicable to that system. DESC will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronic devices (FSC 5962) should contact DESC-EC, telephone (513) 296-6047.

6.4 Comments. Comments on this drawing should be directed to DESC-EC, Dayton, Ohio 45444-5270, or telephone (513) 296-5377.

6.5 Abbreviations, symbols, and definitions. The abbreviations, symbols, and definitions used herein are defined in MIL-I-38535 and MIL-STD-1331.

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6.6 One part - one part number system. The one part - one part number system described below has been developed to allow for transitions between identical generic devices covered by the three major microcircuit requirements documents (MIL-H-38534, MIL-I-38535, and 1.2.1 of MIL-STD-883) without the necessity for the generation of unique PIN's. The three military requirements documents represent different class levels, and previously when a device manufacturer upgraded military product from one class level to another, the benefits of the upgraded product were unavailable to the Original Equipment Manufacturer (OEM), that was contractually locked into the original unique PIN. By establishing a one part number system covering all three documents, the OEM can acquire to the highest class level available for a given generic device to meet system needs without modifying the original contract parts selection criteria.

<u>Military documentation format</u>	<u>Example PIN under new system</u>	<u>Manufacturing source listing</u>	<u>Document listing</u>
New MIL-H-38534 Standard Microcircuit Drawings	5962-XXXXZZ(H or K)YY	QML-38534	MIL-BUL-103
New MIL-I-38535 Standard Microcircuit Drawings	5962-XXXXZZ(Q or V)YY	QML-38535	MIL-BUL-103
New 1.2.1 of MIL-STD-883 Standard Microcircuit Drawings	5962-XXXXZZ(M)YY	MIL-BUL-103	MIL-BUL-103

6.7 Sources of supply.

6.7.1 Sources of supply for device classes Q and V. Sources of supply for device classes Q and V are listed in QML-38535. The vendors listed in QML-38535 have submitted a certificate of compliance (see 3.6 herein) to DESC-EC and have agreed to this drawing.

6.7.2 Approved sources of supply for device class M. Approved sources of supply for class M are listed in MIL-BUL-103. The vendors listed in MIL-BUL-103 have agreed to this drawing and a certificate of compliance (see 3.6 herein) has been submitted to and accepted by DESC-EC.

6.8 Additional information. A copy of the following additional data shall be maintained and available from the device manufacturer:

- a. RHA upset levels.
- b. Test conditions (SEP).
- c. Number of upsets (SEP).
- d. Number of transients (SEP).
- e. Occurrence of latchup (SEP).

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